Hybrid 8j157 Traveler

January 17, 2000

1 Connectivity

Repairs on shorts:

Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 8J157 has die: 202-107 202-108 202-114 202-115 205-030 205-031 205-032 205-033

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 8j157 classification info. Created 16:06:17 01/12/00

Hybrid 8j157 quality: fair
Chip classification: fair good good good good good fair fair
Bad channels (chip-channel): 0-104 6-34
Bad cells: none
Random bad capacitors (chip-cell-channel): 6-2-100 6-2-101 6-3-101
   6-33-35 6-36-35 6-37-35 6-40-35 6-42-35 6-44-35 6-7-33 6-7-35
   6-8-33 6-9-33 6-9-35 7-5-45
Channels at pedestal needed for DCMS: 33.6 32.8 32.6 33.6 30.7 30.5 29.3 31.3
```

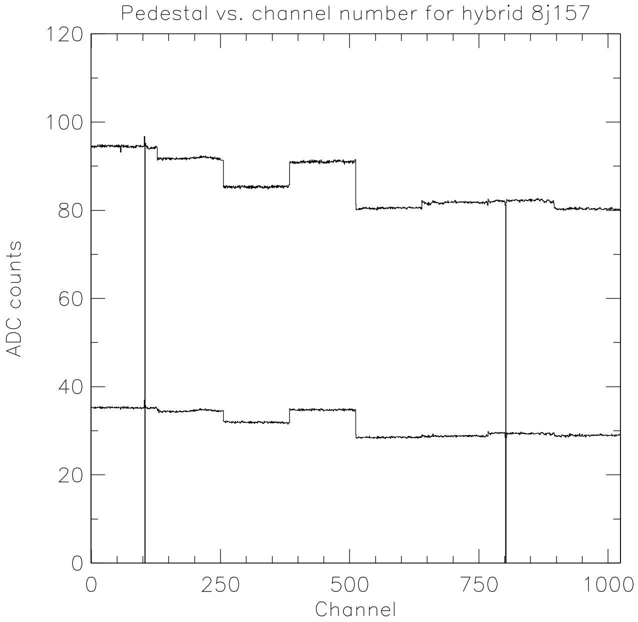
4 Comments

No comments.

5 Pedestal

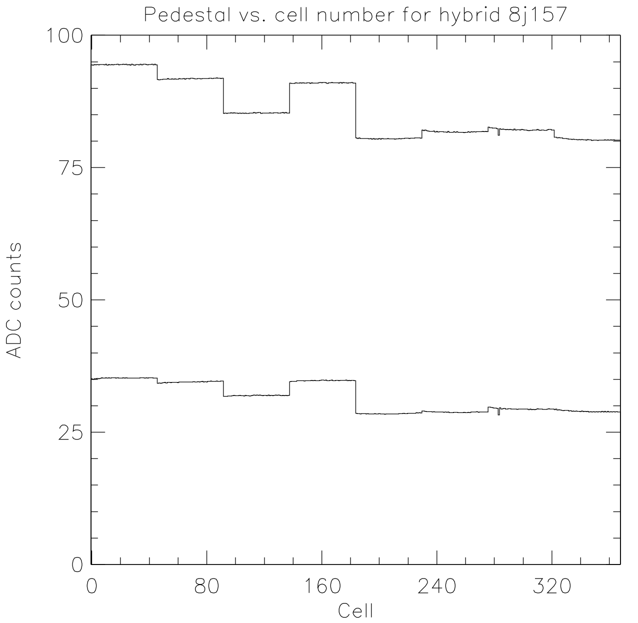
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

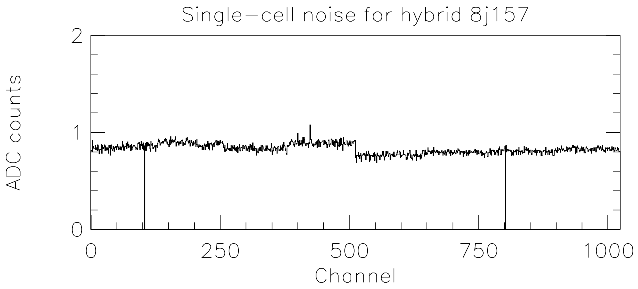
Pedestal vs. Pipeline Cell ID

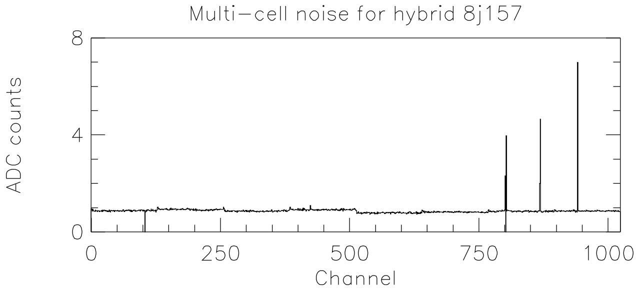


6 Noise

The following plots show the single-cell and multi-cell RMS noise:

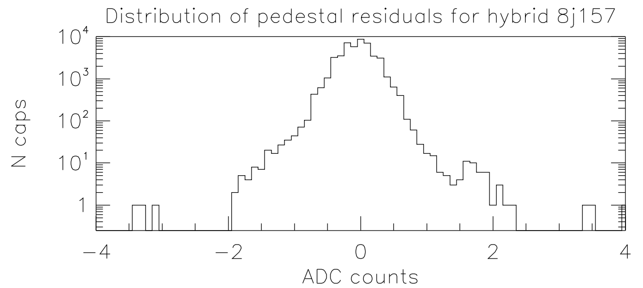
RMS Noise

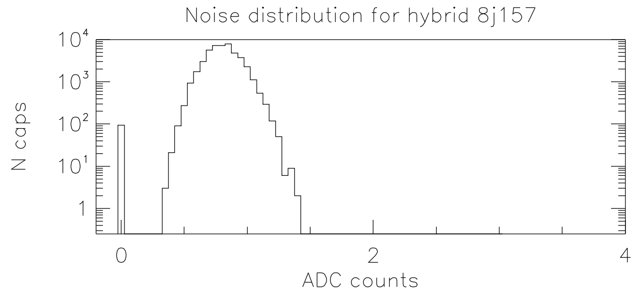




The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise





7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in